## Fifth Semester B.E. Degree Examination, July/August 2022 Fundamentals of CMOS VLSI

Time: 3 hrs. Max. Marks:100

Note: Answer any FIVE full questions, selecting at least TWO full questions from each part.

## PART - A

- a. Explain how the CMOS inverter can act as an amplifier. Describe the function of CMOS differential inverter and discuss the different types of differential amplifiers. (07 Marks)
  - b. Obtain the size of the transistor for a CMOS circuit of 250nm technology has its noise margin  $V_{NML}=0.5V$ , low input voltage is 0.26V. Assume  $V_{DD}=5V$ ,  $V_{TN}=0.7V$ ,  $V_{TP}=-0.8V$ ,  $K_n=150\mu\text{A/v}^2$ ,  $K_p=68\mu\text{A/v}^2$ ,  $W_n=0.5\mu\text{m}$ .

$$\left( \text{Hint} : V_{\text{OL}} = (V_{\text{DD}} - V_{\text{Tn}}) - \sqrt{(V_{\text{DD}} - V_{\text{T}})^2 - \frac{\beta_p}{\beta_n} (V_{\text{DD}} - V_{\text{Tp}})^2} \right).$$
 (07 Marks)

- c. Explain the steps involved in n-MOS fabrication with neat diagram and list out the required number of masks. (06 Marks)
- 2 a. What do you understand about λ-based rules? Draw the schematic and layout for the tristate inverter and mark the width of each layer as per lambda based rule. (08 Marks)
  - b. Discuss the effect of channel length modulation on the performance of nMOS transistor.
  - c. Calculate the delay of the given layer. In  $5\mu m$  technology consider the sheet resistance of metal is  $0.03\Omega$ , sheet resistance of polysilicon is  $25\Omega$  and for n-diffusion is  $10^4\Omega$ . Similarly the relative capacitance for metal is  $0.075\Box C_g$ , for poly  $0.1\Box C_g$  and for diffusion is  $0.25\Box C_g$ . (08 Marks)

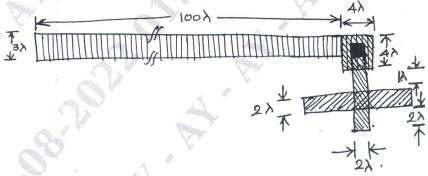


Fig.Q.2(c)

- a. Design a n-MOS pass transistor logic circuit for the sum function of full adder circuit. Show the design with neat steps.
  - b. Draw and explain the circuit of BICMOS inverter and highlight the need for BICMOS technology. (07 Marks)
  - c. Draw the dynamic CMOS logic circuit for the XNOR gate and show clearly how it works as a XNOR gate. (06 Marks)

- 4 a. Draw the rise time and fall time model for 1:1 CMOS inverter and obtain the expression for both rise time and fall time. (06 Marks)
  - b. Scale the below given device parameters:
    - i) Gate Area (A<sub>g</sub>)
    - ii) Gate capacitance (C<sub>g</sub>)
    - iii) Carrier density in channel
    - iv) Channel resistance
    - v) Maximum operating frequency (f<sub>o</sub>)
    - vi) Current density (J).

(06 Marks)

c. Discuss the limitations of scaling.

(08 Marks)

## PART - B

- 5 a. Design the 6-bit structured arbitration logic. Explain the working principle of your design with its circuit diagram and truth table, and also draw the stick diagram for the single structured cell. (08 Marks)
  - b. What do you understand about PLA? Draw the PLA logic circuit for the given expression.

$$Z_1 = a\overline{b}\overline{d}e + a\overline{b}\overline{c}e + bc + de$$

$$Z_2 = \overline{ace} + ce$$

$$Z_3 = bc + de + c de + bd$$
.

(05 Marks)

c. Draw the 3-bit dynamic shift register and explain it briefly.

(07 Marks)

- 6 a. Explain the 12-bit carry skip adder with its architecture for 4 bits in a group and show the  $\pi P_i$  and carry values to add the given numbers. Explain its skipping technique.
  - A = 0010 1011 1000, B = 1100 0000 0111.

(10 Marks)

- b. Explain the arrangement of 4-bit serial parallel multiplier with its block diagram and working principle. (10 Marks)
- 7 a. Explain the pseudo static RAM/register cell with its neat diagram.

(07 Marks)

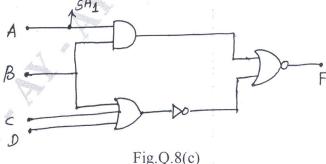
- b. Explain the 3-T dynamic RAM cell with neat sketch. Calculate the number of bits that can be stored in the chip area of 6mm  $\times$  6mm, if the 3T-RAM stores a single bit in the area of  $500\lambda^2$  in 2.5  $\mu$ m technology. (07 Marks)
- c. Explain the pseudo static D-flipflop with neat sketch and define the setup time and holdtime of D-flipflop. (06 Marks)
- 8 a. Define observability and controllability.

(04 Marks)

b. Define stuck-at fault model of digital logic circuits.

(04 Marks)

c. What do you understand about D-algorithm? Explain the algorithm by generating at least one vector for the specified fault in the given circuit. (12 Marks)



F1g.Q.8(